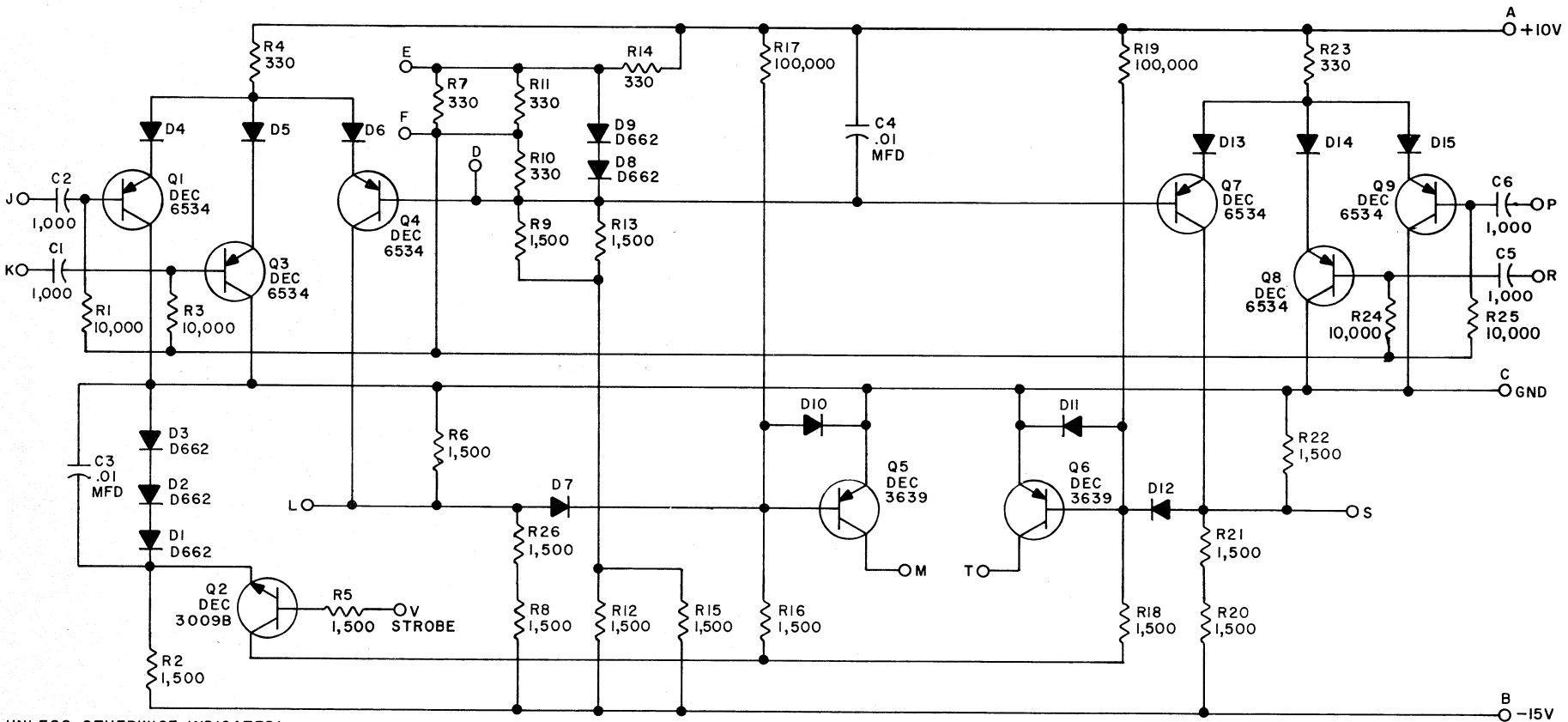
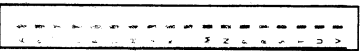


REV. NUMBER 1-0-01 6803-0-1 CS B SIZE

THIS SCHEMATIC IS FURNISHED ONLY FOR TEST AND MAINTENANCE PURPOSES. THE CIRCUITS ARE PROPRIETARY IN NATURE AND SHOULD BE TREATED ACCORDINGLY. COPYRIGHT 1966 BY DIGITAL EQUIPMENT CORPORATION



UNLESS OTHERWISE INDICATED:
 RESISTORS ARE 1/4W; 5%
 DIODES ARE D664
 CAPACITORS ARE MMFD



REVISIONS CHK CHG NO REV	DRN.	DATE	TRANSISTOR & DIODE CONVERSION CHART				digital EQUIPMENT CORPORATION MAYNARD, MASSACHUSETTS	TITLE		
	CHK'D.	DATE	DEC	EIA	DEC	EIA		RECTIFYING SLICER G803		
	ENG.	DATE	DEC 3009B	2N3009				SIZE	CODE	NUMBER
	PROD.	DATE	DEC 3639	2N3639				B	CS	G803-0-1
			DEC 6534	MPS 6534					REV	
			D 6 6 2	IN 6 4 5			PRINTED CIRCUIT REV			
			D 6 6 4	IN 3 6 0 6			A			

DEC FORM NO. DRB 102

SPECS



FLIP CHIP MODULES TEST DATA

TYPE: G803

RECTIFYING SLICER

TEST	CONDITIONS	MINIMUM	MAXIMUM
VOLTAGE D-E	NORMAL POWER	/	-1.2 → -1.4V
VOLTAGE D-F	NORMAL POWER	/	-0.8 → -1.0 V
LOWER LEVEL	STROBE GROUND NO INPUT	-3.2 v	-3.9 v
UPPER LEVEL	STROBE -0.5V, 20MA LOAD ON OUTPUT, -2.0V TO L,S	/	≤ 300 mV
STROBE INPUT CURRENT	V TO GROUND	/	≤ 0.9 MA
TEST POINT L,S	NO INPUT	+1.2 v	+1.6 v
STROBE DISABLE	-2.0V TO STROBE 3V INPUT CHECK FOR NO OUPUT	✓	
SLICE THRESHOLD	-0.5V TO STROBE, VARY INPUT, 1μS WIDE PULSE	-1.2 v	-1.6 v
SLICE TTT	2.4V, 1μS PULSE, GROUND STROBE, 50% TO 50%	RISE	≤ 60 NS
		FALL	≤ 60 NS
STROBE TTT	SAME 50% TO 50%	RISE	≤ 80 NS
OUTPUT PULSE WIDTH	3.0V 20μS WIDE INPUT 50% TO 50%, GROUND STROBE	6 μS	10 μS

TECHNICAL INFORMATION

Instruction literature and technical bulletins are available on all digital products. If you would like to be added to our mailing list for this type of material or if you have any questions about the equipment you have purchased, please contact the nearest Digital Sales Office.

MAINTENANCE INFORMATION

Repair of printed circuitry should be done with a low voltage, fairly cool soldering iron to prevent damage to the transistors and keep the copper from lifting. Oscilloscopes used to troubleshoot a module or system should be grounded to prevent damaging transients.

R. J. Jones
20 July 66

ELEC. TESTER: _____

DATE: 9/12/66